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Introduction

This year we had a very exciting combination of optical system modeling and alignment papers in a combined conference at SPIE Optics + Photonics in San Diego, California, USA. The conference was very successful with high-quality presentations, a poster session, and subsequent proceedings articles. We sincerely thank the speakers and presenters, and the superb community overall for making the sessions and conference such a success. It is very clear that the topics covered by this conference continue to be of great interest to the optics and photonics community.

Six papers related to optical alignment were presented in the first conference session. Five papers on testing, micro lenses, and tolerancing were presented in the second session, and 14 papers were presented on optical modeling and performance predictions over four sessions that covered, respectively: session three - optical distortion, optomechanics, and thermo-optical engineering; session four - stray light; session five - component models, and session six - communication systems and silicon photonics.

We must of course thank our excellent program committee for continuing to promote this conference. Furthermore, we are once again quite grateful to the greater community for sharing work and participating, as interaction in this area is very beneficial in advancing our field. Finally, we thank the fine volunteers and the SPIE staff for providing us the opportunity to cover the subjects of optical system alignment, tolerancing, verification, and modeling/performance-predictions in a dedicated conference and proceedings.

The Optical Modeling and Performance Predictions and Optical System Alignment, Tolerancing, and Verification conferences will continue in 2020. We encourage everyone interested in these useful topics to look for the call for papers and to submit your work in early 2020. Please feel free to contact us or anyone on our program committee if you have any questions.

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